

**Search Notes**

Application/Control No.

10/776,259

Examiner

Le Nguyen

Applicant(s)/Patent under  
Reexamination

TAGUCHI, TERUTOSHI

Art Unit

2174

**SEARCHED**

Class	Subclass	Date	Examiner
715	763	8/8/2007	LVN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
US-PG Pub, USPAT: 715/763		8/8/2007	LVN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
US-PG Pub, USPAT: 715/502,964,763; 345/419,420	8/8/2007	LVN
East, all databases incl. EPO, JPO	8/16/2007	LVN
IEEE Xplore, ACM	8/16/2007	LVN